

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Hitoshi HIRAKAWA, et al.

Application No.:

Group Art Unit:

Filed: September 15, 2003

Examiner:

For: METHOD FOR DRIVING PLASMA DISPLAY PANEL AND PLASMA DISPLAY DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:
 - 1a. ☒ Form PTO-1449.
 - 1b. ☒ Copies of IDS citations.
 - 1c. ☐ An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
 - 1d. ☒ English language translation (complete or relevant portion(s)) attached to each non-English language publication.
 - 1e. ☒ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.
2. ☒ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is

(Check appropriate Items 2a, 2b, 2c and/or 2d)
 - 2a. ☐ satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
 - 2b. ☒ set forth in the application.

- 2c. ☒ satisfied because an English language translation (complete or relevant portion(s)) is attached to each non-English language publication.
- 2d. ☒ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>	ATTORNEY DOCKET NO. 122.1568	APPLICATION NO.
	FIRST NAMED INVENTOR Hitoshi HIRAKAWA, et al.	
	FILING DATE September 15, 2003	GROUP ART UNIT

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA	6,489,727	12/2002	Kanazawa			
	AB	2002-0167466 A1	11/2002	Setoguchi et al.			
	AC	6,373,452	04/2002	Ishii et al.			
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
	AG	2002-72961	03/2002	Japan				X
	AH	2000-75835	03/2000	Japan				X
	AI	9-160525	06/1997	Japan				X
	AJ	5-313598	11/1993	Japan			abs	
	AK	3-219286	09/1991	Japan			abs	
	AL	2000-148085	05/2000	Japan			abs	

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	AM	
	AN	
	AO	

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

ATTACHMENT 1(e)

EXPLANATIONS OF RELEVANCY OF REFERENCES	ATTORNEY DOCKET NO. 122.1568	APPLICATION NO.
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Japanese reference AG corresponds to U.S. reference AA.

Japanese reference AH corresponds to U.S. reference AB.

Japanese reference AI corresponds to U.S. reference AC.

Japanese reference AL discloses a constitution in which a reset operation is carried out in a desired SF in a frame.